Behavior and performance evaluation of Windows Embedded Compact 7 on ARM

Copyright

Disclaimer

Although all care has been taken to obtain correct information and accurate test results, Dedicated Systems Experts, VUB-Brussels, RMA-Brussels and the authors cannot be liable for any incidental or consequential damages (including damages for loss of business, profits or the like) arising out of the use of the information provided in this report, even if these organizations and authors have been advised of the possibility of such damages.

Authors

Luc Perneel (1, 2), Hasan Fayyad-Kazan(2) and Martin Timmerman (1, 2, 3)
1: Dedicated Systems Experts, 2: VUB-Brussels, 3: RMA-Brussels

http://download.dedicated-systems.com E-mail: info@dedicated-systems.com

EVALUATION REPORT LICENSE

This is a legal agreement between you (the downloader of this document) and/or your company and the company DEDICATED SYSTEMS EXPERTS NV, Diepenbeemd 5, B-1650 Beersel, Belgium.
It is not possible to download this document without registering and accepting this agreement on-line.

1. **GRANT**. Subject to the provisions contained herein, Dedicated Systems Experts hereby grants you a non-exclusive license to use its accompanying proprietary evaluation report for projects where you or your company are involved as major contractor or subcontractor. You are not entitled to support or telephone assistance in connection with this license.
2. **PRODUCT**. Dedicated Systems Experts shall furnish the evaluation report to you electronically via Internet. This license does not grant you any right to any enhancement or update to the document.
3. **TITLE**. Title, ownership rights, and intellectual property rights in and to the document shall remain in Dedicated Systems Experts and/or its suppliers or evaluated product manufacturers. The copyright laws of Belgium and all international copyright treaties protect the documents.
4. **CONTENT**. Title, ownership rights, and an intellectual property right in and to the content accessed through the document is the property of the applicable content owner and may be protected by applicable copyright or other law. This License gives you no rights to such content.
5. **YOU CANNOT**:
   - You cannot, make (or allow anyone else make) copies, whether digital, printed, photographic or others, except for backup reasons. The number of copies should be limited to 2. The copies should be exact replicates of the original (in paper or electronic format) with all copyright notices and logos.
   - You cannot, place (or allow anyone else place) the evaluation report on an electronic board or other form of on line service without authorisation.
6. **INDEMNIFICATION**. You agree to indemnify and hold harmless Dedicated Systems Experts against any damages or liability of any kind arising from any use of this product other than the permitted uses specified in this agreement.
7. **DISCLAIMER OF WARRANTY**. All documents published by Dedicated Systems Experts on the World Wide Web Server or by any other means are provided "AS IS" WITHOUT WARRANTY OF ANY KIND, EITHER EXPRESSED OR IMPLIED, INCLUDING, BUT NOT LIMITED TO, THE IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE, OR NON-INFRINGEMENT. This disclaimer of warranty constitutes an essential part of the agreement.
8. **LIMITATION OF LIABILITY**. Neither Dedicated Systems Experts nor any of its directors, employees, partners or agents shall, under any circumstances, be liable to any person for any special, incidental, indirect or consequential damages, including, without limitation, damages resulting from use of OR RELIANCE ON the INFORMATION presented, loss of profits or revenues or costs of replacement goods, even if informed in advance of the possibility of such damages.
9. **ACCURACY OF INFORMATION**. Every effort has been made to ensure the accuracy of the information presented herein. However Dedicated Systems Experts assumes no responsibility for the accuracy of the information. Product information is subject to change without notice. Changes, if any, will be incorporated in new editions of these publications. Dedicated Systems Experts may make improvements and/or changes in the products and/or the programs described in these publications at any time without notice. Mention of non-Dedicated Systems Experts products or services is for information purposes only and constitutes neither an endorsement nor a recommendation.
10. **JURISDICTION**. In case of any problems, the court of BRUSSELS-BELGIUM will have exclusive jurisdiction.

Agreed by downloading the document via the internet.

DOCUMENT CHANGE LOG

Issue No.	Revised Issue Date	Para's / Pages Affected	Reason for Change
1.01	July 18, 2011	All	Initial draft
1.02	July 27, 2011	All	comments
2.00	July 28, 2011	All	QA version
3.00	October 28, 2011	All	New BSP
4.00	November 30, 2011	All	Verifying text
4.1	December 25, 2011	All	Change pages' header
5	Feb 18, 2012	All	Add MS feedback, change structure
5.1	June 6, 2012		Add vendor comments

1 Document Intention

1.1 Purpose and scope

This document presents the quantitative evaluation results of the **Windows Embedded Compact 7** OS on ARM-based platform.

The layout of this report follows the one depicted in "The OS evaluation template" [Doc. 4]. The test specifications can be found in "The evaluation test report definition" [Doc. 3]. For more detailed references, See section "Related documents" of this document. These documents have to be seen as an integral part of this report!

Due to the tightly coupling between these documents, the framework version of "The evaluation test report definition" has to match the framework version of this evaluation report (which is 2.9). More information about the documents and tests versions together with their corresponding relation between both can be found in "The evaluation framework", see [Doc. 1] in section "Related documents" of this document.

The generic test code used to perform these tests can be downloaded on our website by using the link in the "related documents" section.

1.2 Test framework used: 2.9

This document shows the test results in the scope of the evaluation framework 2.9. More details about this framework are found in Doc 1 (see section "Related documents").

1.3 Conventions

Throughout this document, we use certain typographical conventions to distinguish technical terms. Our used conventions are the following:

- ***Bold Italic*** for OS Objects
- **Bold** for Libraries, packets, directories, software, OSs...
- `Courier New` for system calls (APIs...)

1.4 Related documents

These are documents that are closely related to this document. They can all be downloaded using following link:
http://www.dedicated-systems.com/encyc/buyersguide/rtos/evaluations

Doc. 1 The evaluation framework
This document presents the evaluation framework. It also indicates which documents are available, and how their name giving, numbering and versioning are related. This document is the base document of the evaluation framework.
EVA-2.9-GEN-01 Issue: 1 Date: April 19, 2004

Doc. 2 What is a good RTOS?
This document presents the criteria that Dedicated Systems Experts use to give an operating system the label “Real-Time”. The evaluation tests are based upon the criteria defined in this document.
EVA-2.9-GEN-02

Doc. 3 The evaluation test report definition
This document presents the different tests issued in this report together with the flowcharts and the generic pseudo code for each test. Test labels are all defined in this document.
EVA-2.9-GEN-03 Issue: 1 April 19, 2004

Doc. 4 The OS evaluation template
This document presents the layout used for all reports in a certain framework.
EVA-2.9-GEN-04 Issue: 1 April 19, 2004

Doc. 5 Windows Embedded Compact 7, Theoretical evaluation.
This document presents the qualitative discussion of the OS
EVA-2.9-OS-CE-7 Issue: 1 May 20, 2011

2 Introduction

This chapter talks about the OS that we are going to test and evaluate, and the hardware on which the under testing OS will be employed to be tested.

2.1 Overview

Releasing a new OS with a different name (changed from **Windows CE** to **Windows Embedded Compact 7**) does not mean that we are up with a new OS! Such naming change was mainly done for marketing purposes, as there were no fundamental changes in the OS itself!

Further in the document, the full name "**Windows Embedded Compact 7**" or the short names "**Compact 7**" and "**CE7**" will be used.

2.2 Evaluated (RTOS) Product

This section describes the OS that Dedicated Systems tested using their Evaluation Testing Suite, and the hardware on which this OS was running during the testing.

2.2.1 Software

The RTOS that will be evaluated and tested is **Windows Embedded Compact 7**. This OS was launched by Microsoft Corporation at the beginning of 2011. In fact, this OS "**Windows Embedded Compact**" is the successor of **Windows CE6R3**.

The tests for evaluating this OS were done in July 2011.

2.2.2 Hardware

We tested the **Windows Embedded Compact 7** on a Beagle-XM Board Rev C. this platform has the following characteristics;

- based on the Texas Instruments DM3730 Digital Media Processor
- ARM Cortex A8 running at 1GHz
- L1 Cache: 32KB instruction and 32KB data cache
- L2 Cache: 64KB
- 512MB Ram at 166MHz
- BSP: MPC-Data version of the BSP.

3 Evaluation results summary

Following is a summary of the results of evaluating **Windows Embedded Compact 7**.

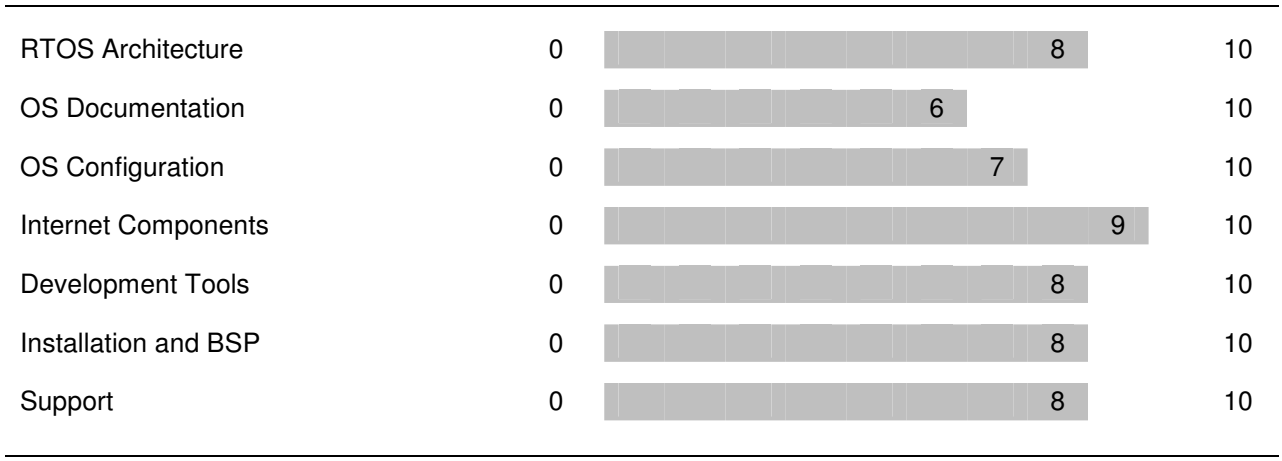
3.1 Positive points

1) All protection primitives use priority inheritance, which is a major plus for achieving real-time behavior
2) Good debugging tools: Available also for kernel/driver debugging.
3) Very easy to install and to set-up a target (from templates).
4) Provides the same flexibility as a 32-bit general purpose OS

3.2 Negative points (see Microsoft's comments in section 3.4)

1) The operating system documentation has taken a step backwards compared with the previous versions. A lot of background information is removed (***see MS comments***).
2) Customizing the kernel and adding custom drivers (BSP) stays a daunting task once you go away from the default configurations.
3) The remote tool has been changed since last version. We noticed two issues, the more important of which is that there is no officially-supported method to include the remote tools within a device image using Platform Builder. Additionally, we noticed during our testing that establishing a connection between the tools and the target took in excess of a minute, which was longer than our expectation (***see MS comments***).

3.3 Ratings



3.4 Vendor Comments

Following are the comments of Microsoft on the negative points:

- **For point 1** Microsoft notes that documentation is a focus for the next release, and the product team plans to bring forward any relevant content from earlier releases, which will be identified as still applicable to the current release.
- **For point 3** Microsoft notes that the ability to add the remote tools to a device image using Platform Builder is by design, as generally a finished device's final image would not normally include debug support. Additionally, because some devices won't have a .CAB installer, making installation of the remote tools a challenge. They are investigating now how to provide this support in a future release of Platform Builder. Microsoft also notes that the Compact Product Team was unable to reproduce the delayed connection time experienced by Dedicated Systems but will continue to investigate whether connection time is a persistent issue.

4 Test Results

Test Results	0	8	10

As usual, Compact 7 real-time behavior is excellent. One thing that could be improved on this specific platform is the clock tick duration which is rather large.

4.1 Calibration system test (CAL)

"Calibration tests" are performed to calibrate the tracing overhead compared with the processing power of the platform. Such tests are important to understand the accuracy of the measurements done in scope of this report, and for measuring the processing power of the platform. This calibration permits comparison with the results on other platforms.

4.1.1 Tracing overhead (CAL-P-TRC)

As the Beagle board does not have any PCI support, we used the on-chip hardware timers for our measurements.

"Tracing overhead test" calibrates the tracing system overhead. It is more related to the hardware than the OS because its aim is to correct the measured time values.

In the rest of the document, the tracing overhead is subtracted from the obtained results.

For tracing, an internal General Purpose (GP) timer running at 26 MHz was used. Reading out these timers takes some overhead of course; however, there is not any jitter at all in the overhead of the trace which in turn does not generate much extra inaccuracies.

In general, the results in this report are correct to +/- 0.2 µseconds. Therefore the results shown in the tables are rounded to 0.1 microseconds.

4.1.1.1 Test results

Test	result
Average tracing overhead	307 nsec
minimum tracing overhead	307 nsec
maximum tracing overhead	307 nsec

4.1.2 CPU power (CAL-P-CPU)

The "CPU power" test calibrates the CPU performance and the memory bandwidth of the used platform. This test is measured in different situations, starting from the situation where code and data are cached, until the situation where neither code nor data are cached. With such different situation tests, the effects of the cache can be calculated.

We have been seriously reworking this test lately. The CPU test uses only one data address; The non-cached version is about 128KB in size (instructions), while the cached version uses a loop (a bit unrolled to have a small loop overhead but so it fits in the L1 I-cache and it uses only two data words). The instruction cache test is done twice:

- The instructions have not been mapped yet (leading to TLB exceptions and page faults)
- There will not be any page faults (TLB exceptions will still happen).

This gives us some indication about the impact of page faults.

For this specific ARM platform, we used a factor 5 for the test, so that 5 x 128KB = 640KB is larger than the L1/L2 caches. After the test, we divide the results by 5, in order to be capable to compare the results with other platforms

Further, we divided the data cache tests into a read test (reading content of a large array in non-cached case, and read a small array in a loop in the cached case) and a write test. Remark that we flush the caches in between the tests.

This rework shows that a worst-case / best-case scenario can cause significant performance impacts, something that in reality will almost surely never be that large (or you should be able to run everything using only L1 caches).

The impact of either having the code in the I-Cache or not, has serious effect on the results of the tests.

Remark that the results of such tests will depend also, to a high extent, on the cache organization:

- Number of ways
- Line size
- Number of address bits used for index
- Virtual or physical addresses used as index.

4.1.2.1 Test results

The results for our Pentium II 233 MHz platform running Compact 7, averaged over 10 tests, are shown below as a reference:

Test	no cache	cached	cache effect
CPU test: first load.	1.450 ms		
CPU test: ICache effect	500.5 us	216.8 us	2.4
MEM write test	333.6 us	309.2 us	1.1
MEM read test	253.2 us	166.4 us	1.5
Average caching effect (CPU and MEM)			1.7

The results for the same code for **Compact 7** on the Beagle-XM are shown below:

Test	no cache	cached	cache effect
CPU test: first load.	352.8 us		
CPU test: ICache effect	261.5 us	27.9 us	9.3
MEM write test	26.6 us	26.2 us	1.0
MEM read test	43.4 us	19.6 us	2.2
Average caching effect (CPU and MEM)			4.2

Comparing both platforms show the enormous increase in speed! Besides un-cached code, which is only twice faster (x86 code is more compact than ARM), others are up to ten times faster. It is however remarkable that in the other test concerning performance of system calls, the difference is much smaller than what you would expect from these tests.

Here are some conclusions regarding the Beagle-XM ARM:

- Caching of instructions has a huge impact! This is logical because for each instruction, memory has to be fetched containing this instruction. When handling data, you will always have some instructions without data access (register manipulations and operations) which are not impacted by the data cache.
- Caching does NOT have a huge impact on data writes: writes can be postponed, so they do not block the next instructions in the pipeline from executing.

- Caching has a much larger impact on data reads: instructions have to wait until the data becomes available. This will take longer if this data is not cached compared to the case where it is.

Clearly, interrupt handlers and other code with real-time requirements can be much slower if they are not in the cache.

The results cannot be completely compared with other tests that we did on the same platform. Even if the same code is used, these figures can be different depending on compiler optimizations and compiler versions.

4.2 Clock tests (CLK)

"Clock tests" measure the time needed by the operating system to handle its clock interrupt. On the tested platform, the clock tick interrupt is set on the highest hardware interrupt level, interrupting any other thread or interrupt handler.

4.2.1 Operating system clock setting (CLK-B-CFG)

The "OS clock setting" test examines the setting of the clock tick period in the operating system. This test shows the default clock timing as they are set by the BSP and/ or the kernel.

Remark that when execute `sleep (0)`, the call will immediately return (if no other threads are running at the same priority level). Other sleeps behave normal. Microsoft provides a `SleepTillTick()` call for this purpose:

Thus in practice:

- `Sleep(0)` will not sleep, but will yield if there is another thread of same priority runnable.
- `SleepTillTick()` will sleep between 0-1 ms.
- `Sleep(n)` will sleep between n and (n-1) ms.

4.2.1.1 Test results

Test	result
Test succeeded	Yes(sleepTillTick)
Tested clock period	1ms
Clock period adaptable	NO

4.2.2 Clock tick processing duration (CLK-P-DUR)

The "clock tick processing duration" test examines the clock tick processing duration in the kernel. The test results are extremely important, as the clock interrupt will disturb all the other performed measurements. Using a tickles kernel will not even prevent this from happening (it will only lower the number of occurrences). The kernel under test was not using the tickles timer option.

The bottom line of the figures in section 4.2.2.2 represents the normal loop time of the test if no clock interrupt occurs during the test loop. The upper line is generated by the samples when a clock interrupt occurred during the loop. The difference between the two lines is the clock tick processing duration.

Be careful; the OAL layer may stop the clock tick interrupt if not needed (tickles kernel). However, this will happen only if the CPU load is minimal, in which case the used memory bandwidth will be small.

☹ The strange thing is that the clock interrupt on this platform/BSP takes almost twice the time compared with the tests on the Pentium II 233MHz platform! For most other tests, this platform is much faster than the Pentium II 233MHz, but still the clock duration is longer.

We note that the clock tick subsystem is largely controlled via OEM calls, which means that performance is dependent on the quality of the BSP, which in this case came from a 3rd party. Microsoft assured for us that for any future Compact evaluations, they would provide us a BSP verified by them. Looking at the very good results they are able to achieve on PC hardware (where the BSP is indeed made by Microsoft) we have no doubt that this will be the case as well if Microsoft makes the ARM BSP.

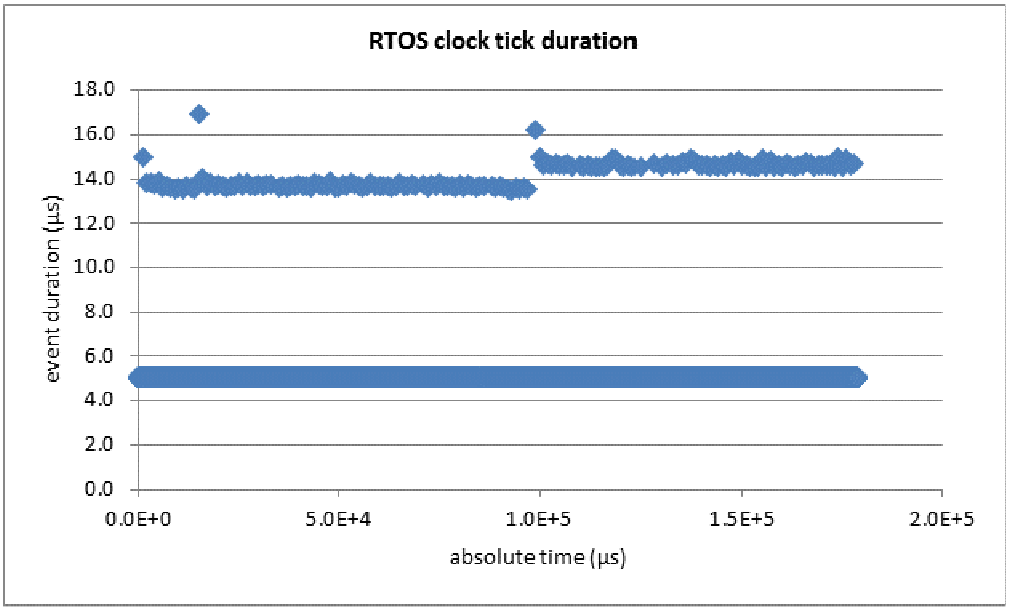
Another strange aspect of this BSP was that after 100ms full load, the clock tick starts suddenly to take longer (from 8.5 to 9.5us).

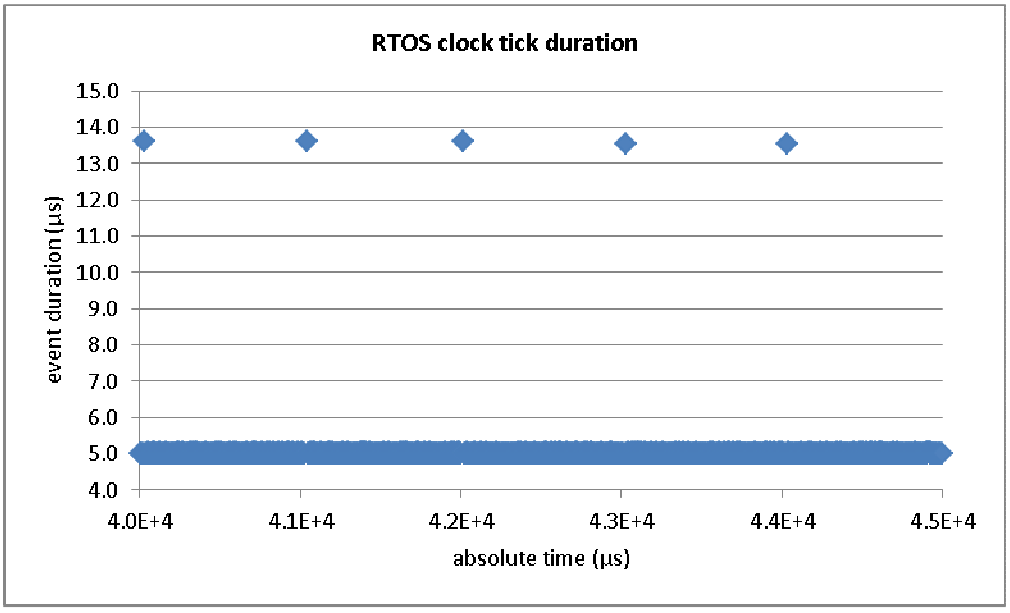
This will be detected in different other tests further in this document.

4.2.2.1 Test results

Test	result
CLOCK_LOOP_COUNTER	1000
Normal busy loop time	5.0 µs
Busy loop time with clock interrupt	13.5 µs, worst case 17 µs
Clock interrupt duration	8.5 µs to 12 us

4.2.2.2 Diagrams





Zoomed in extract from diagram above.

4.3 Thread tests (THR)

"Thread tests" measure the scheduler performance.

4.3.1 Thread creation behaviour (THR-B-NEW)

The "thread creation behavior" test examines the OS behavior when it creates threads. This test attempts to answer the question: Does the OS behave as it should in order to be considered a real-time operating system? Following scenarios are tested:

- If a thread is created with a lower priority than the creating thread, then are we sure that it is not activated until the creating thread is finished?
- If a thread is created with the same priority as the creating thread, will it be placed at the ready tail?
- When yielding after the creation in the above test, does the newly created thread becomes active?
- If a thread is created with a higher priority than the creating thread, is it then immediately activated?

This test succeeded without any problems.

4.3.1.1 Test results

Test	result
Test succeeded	YES
Lower priority not activated?	YES
Same priority at tail?	YES
Yielding works?	YES
Higher priority activated?	YES

4.3.2 Round robin behaviour (THR-B-RR)

The "round robin behavior" test checks if the scheduler uses a fair round robin mechanism to schedule threads that use the SCHED_RR scheduling policy, are of the same priority, and are in the ready-to-run state (and using)!

☹ A problem was detected here: the first time a thread becomes active, it takes a longer time slice (100ms) than in the other cases (1ms = clock tick).

We took a look back to the test results of **CE 6.0** and discovered that the same problem was indeed present there as well. To be sure that we didn't do anything wrong in the test, we compared the code for this test with the test code of other RTOS which did not have this behavior and no differences were found.

Although it is strange behavior, creating dynamically the threads in a real-time system is a bad practice which is normally never done. As such, this problem will not have any impacts in real use cases.

4.3.2.1 Test results

Test	result
Test succeeded	No (first time slice after thread creation is longer)
RR Time slice following this test	1 clock tick normally (first slice takes 100 clock ticks)

4.3.3 Thread switch latency between same priority threads (THR-P-SLS)

The "thread switch latency between same priority threads" test measures the time needed to switch between threads of the same priority. For this test, threads must voluntarily yield the processor for other threads.

In this test, we use the SCHED_FIFO policy. If we do not use the "first in first out" policy, a round-robin clock event could occur between the yield and the trace, so that the thread activation is not seen in the trace.

This test was performed in order to generate the worst-case behavior. We performed the test with an increasing number of threads, starting with two (2) and going up to 1000 in order to observe the behavior in a worst-case scenario. As we increase the number of active threads, the caching effect becomes evident since the thread context will no longer be able to reside in the cache (on this platform the L1 caches are 32KB, both for the data as the instruction cache).

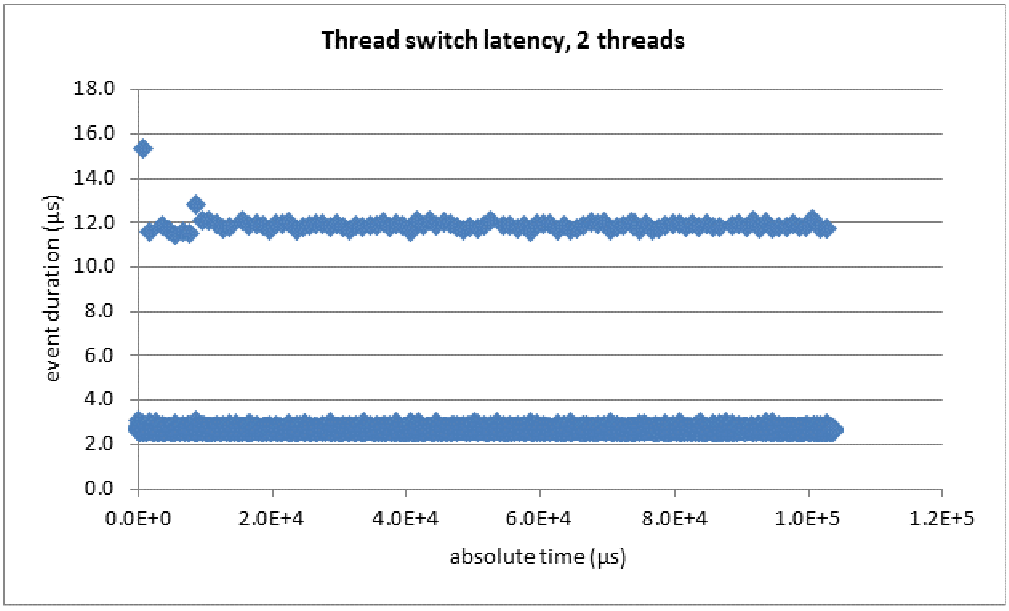
As loading/starting the test software passes a lot of code and data to the processor, the first clock tick will not be cached in L2 (causing the peak for the first clock tick in the 2 thread scenarios). Once there are enough running threads, the clock interrupt will be always un-cached and thus the clock tick interrupt becomes more important.

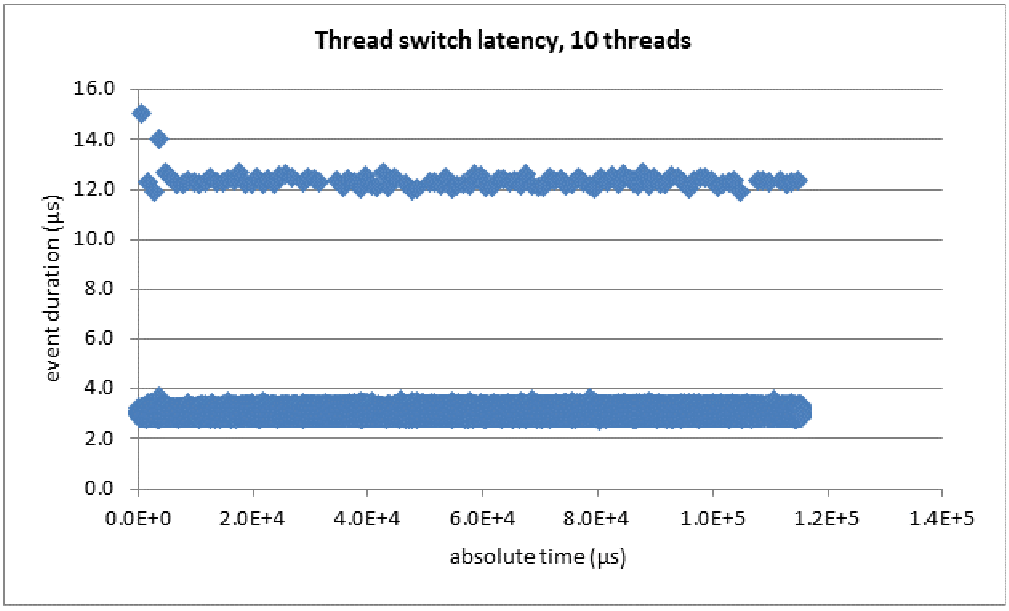
4.3.3.1 Test results

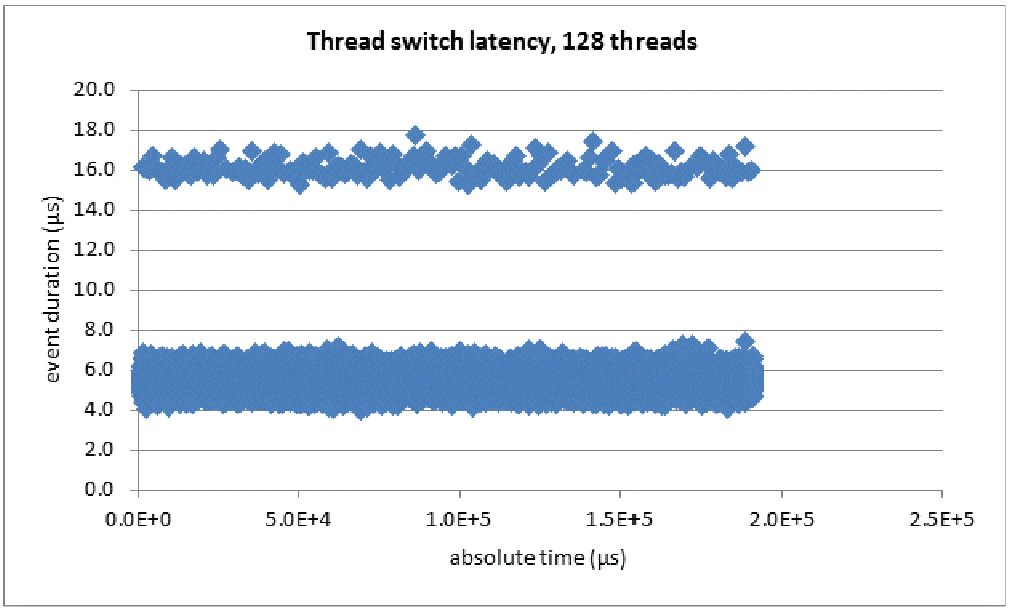
Test	result
Test succeeded	YES

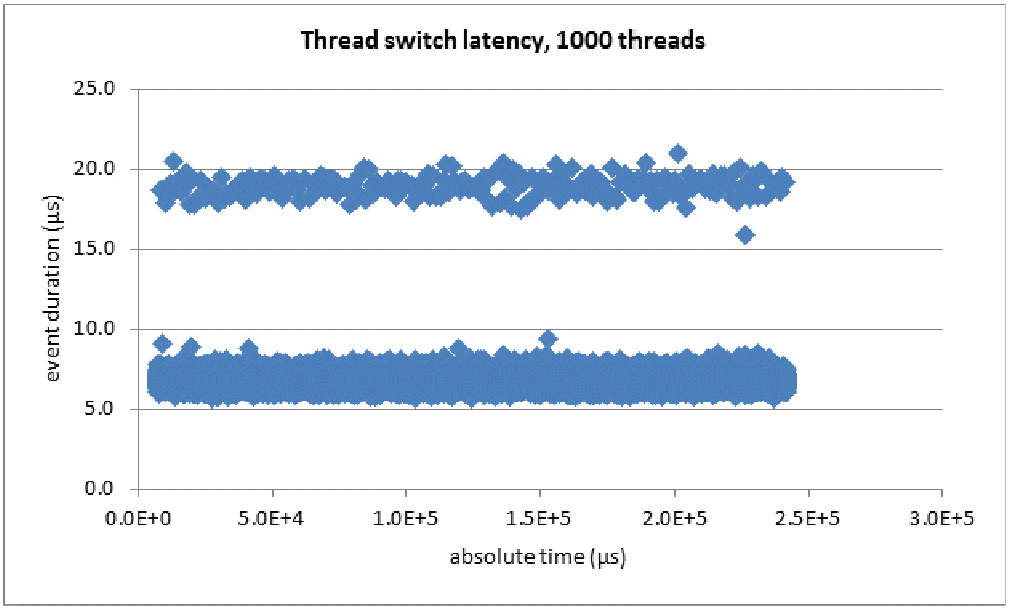
Test	Sample qty	Avg	Max	Min
Thread switch latency, 2 threads	31501	2.7 µs	15.3 µs	2.5 µs
Thread switch latency, 10 threads	31501	3.1 µs	15.1 µs	2.7 µs
Thread switch latency, 128 threads	31501	5.5 µs	17.7 µs	4.0 µs
Thread switch latency, 1000 threads	31501	6.9 µs	21.0 µs	5.7 µs

4.3.3.2 Diagrams









4.3.4 Thread creation and deletion time (THR-P-NEW)

The "thread creation and deletion time" test examines the time required to create a thread, and the time required to delete a thread in the following different scenarios:

- Scenario 1 "never run": The created thread has a lower priority than the creating thread and is deleted before it has any chance to run. No thread switch occurs in this test.
- Scenario 2 "run and terminate": The created thread has a higher priority than the creating thread and will be activated. The created thread immediately terminates itself (thread does nothing).
- Scenario 3 "run and block": The same as the previous scenario (scenario 2: run and terminate), but the created thread does not terminate (it lowers its priority when it is activated).

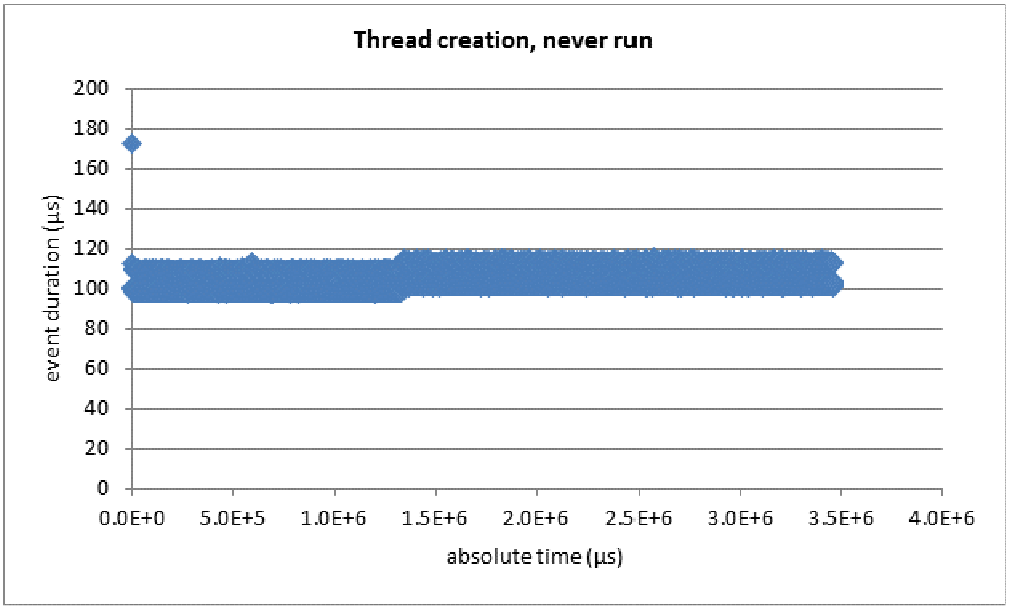
In the scenarios where the thread actually runs (2 and 3), the creation time is measured as the duration from the system call creating the thread until the time when the created thread is activated. For the "never run" scenario, the creation time is measured as the duration of the system call.

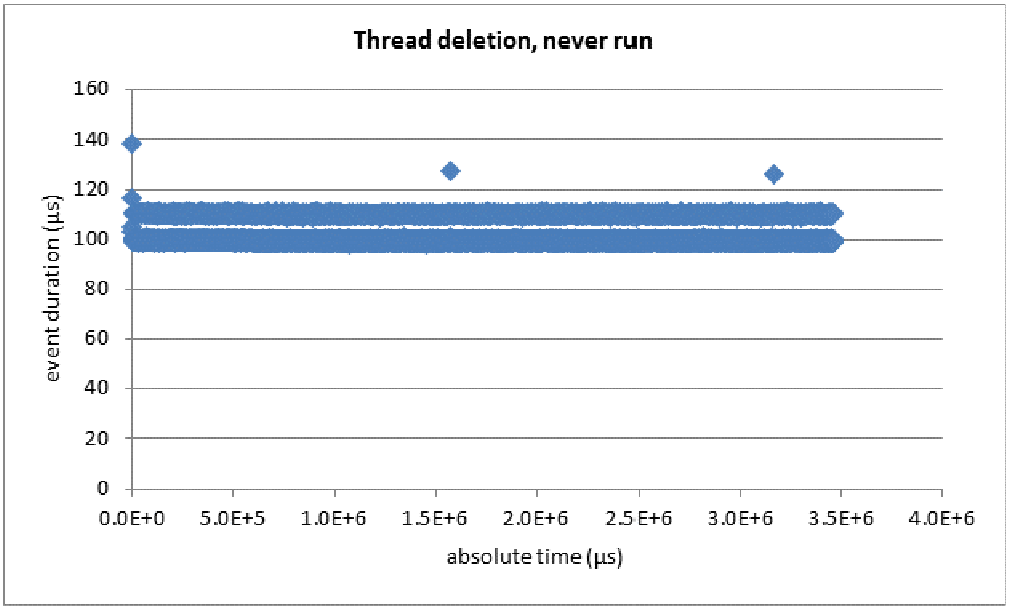
4.3.4.1 Test results

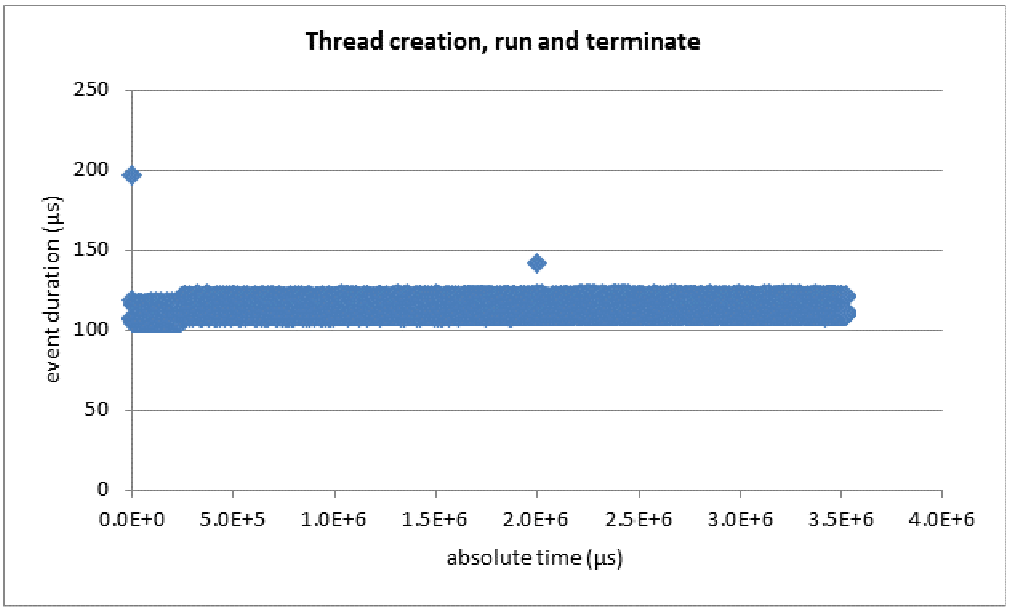
Test	result
Test succeeded	YES

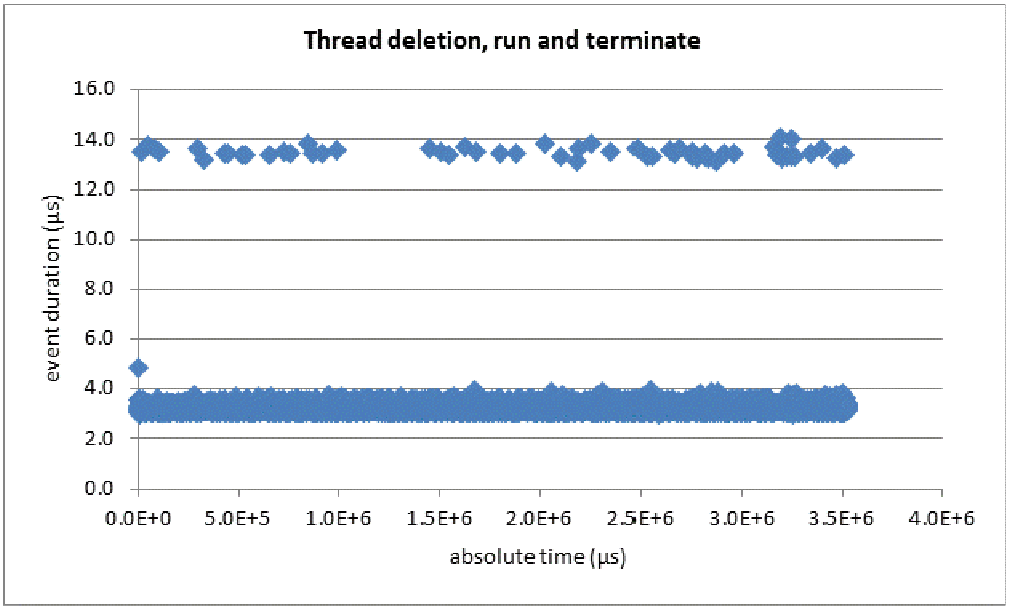
Test	Sample qty	Avg	Max	Min
Thread creation, never run	16383	102 µs	173 µs	97.7 µs
Thread deletion, never run	16383	100 µs	139 µs	98.0 µs
Thread creation, run and terminate	16383	111 µs	197 µs	104 µs
Thread deletion, run and terminate	16383	3.3 µs	14.1 µs	3.0 µs
Thread creation, run and block	16383	110 µs	189 µs	105 µs
Thread deletion, run and block	16383	101 µs	133 µs	98.6 µs

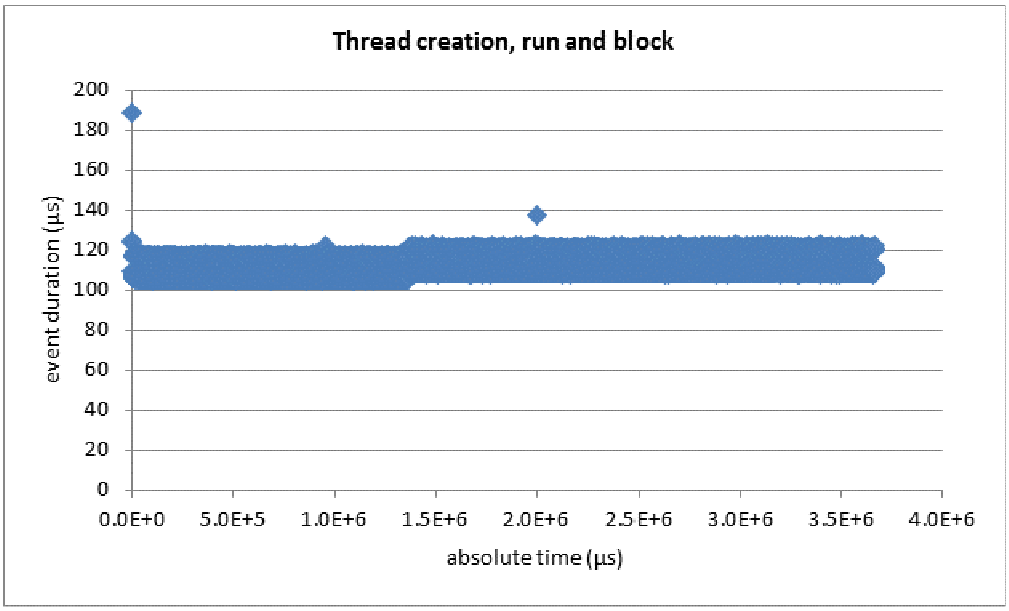
4.3.4.2 Diagrams

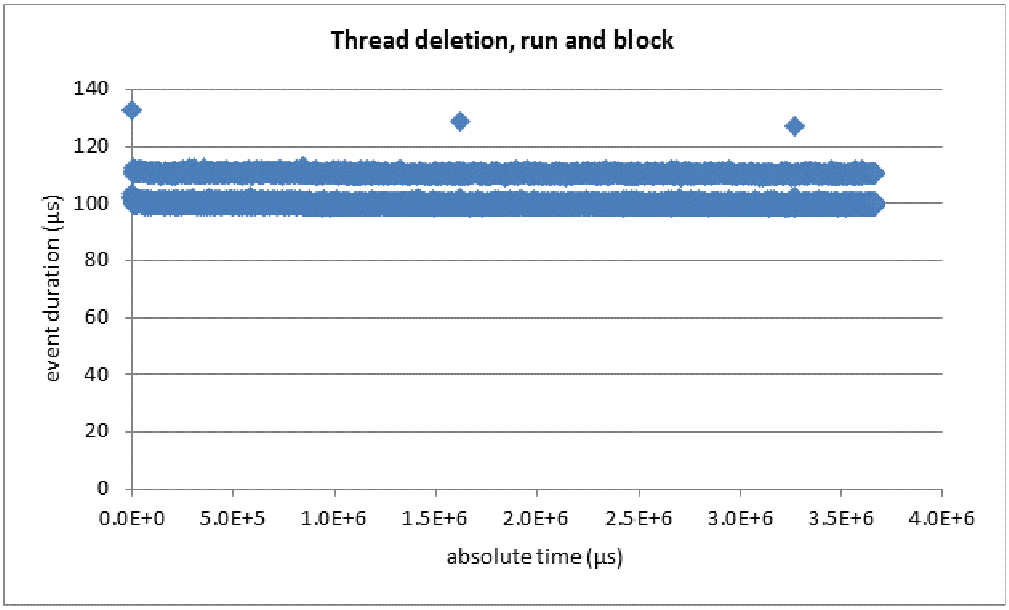












4.4 Semaphore tests (SEM)

"Semaphore tests" examine the behavior and performance of the OS counting semaphore. The counting semaphore is a system object that can be used to synchronize threads.

4.4.1 Semaphore locking test mechanism (SEM-B-LCK)

In this test, we verify if the counting semaphore locking mechanism works as it is expected to work. If this mechanism works as expected, then:

- The P () call will block only when the count is zero.
- The V () call will increment the semaphore counter.
- In the case where the semaphore counter is zero, the V () call will cause a rescheduling by the OS, and blocked threads may become active.

The semaphore behaves correctly as a protection mechanism.

4.4.1.1 Test results

Test	result
Test succeeded	YES
Maximum semaphore value?	Limited by the "int" type
Rescheduling on free?	OK

4.4.2 Semaphore releasing mechanism (SEM-B-REL)

The "semaphore releasing mechanism" test verifies that the highest priority thread being blocked on a semaphore will be released by the release operation. This action should be independent of the order of the acquisitions taking place.

Compact 7 passed this test.

4.4.2.1 Test results

Test	result
Test succeeded	YES

4.4.3 Time needed to create and delete a semaphore (SEM-P-NEW)

The "time needed to create and delete a semaphore" test is performed to gain an insight about the time needed to create a semaphore and the time needed to delete it. The deletion time is checked in two cases:

- The ***semaphore*** is used between the creation and deletion.
- The ***semaphore*** is NOT used between the creation and deletion.

Remark that although we do not use "named" ***semaphores***, there seems to be a system call required to create/delete a semaphore.

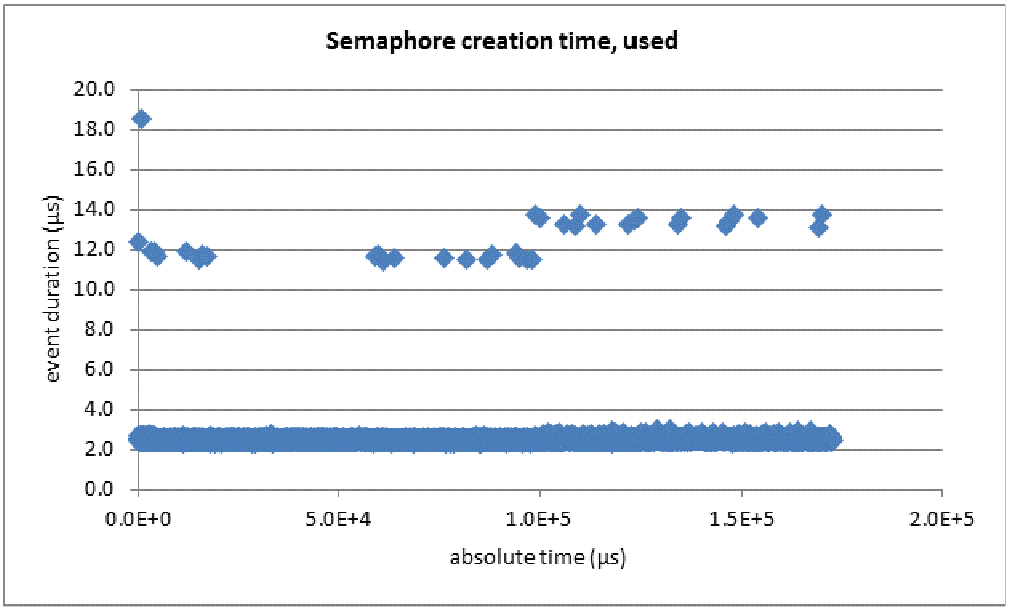
The clock tick line is clearly visible (Diagrams of section 4.4.3.2). On some diagrams, you can see that the clock interrupt starts to take a bit longer once there is more than 100ms full CPU load.

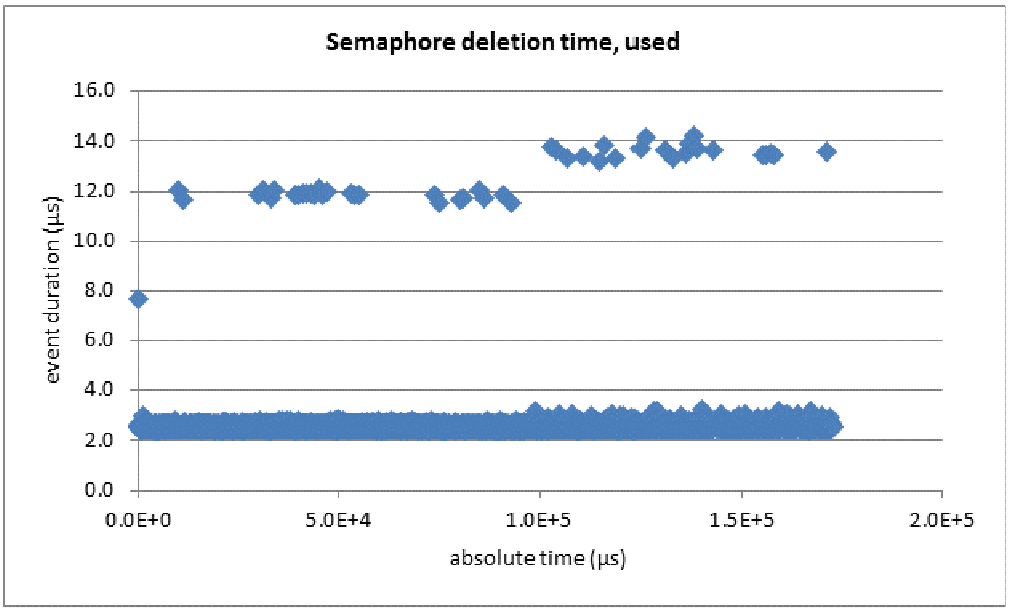
4.4.3.1 Test results

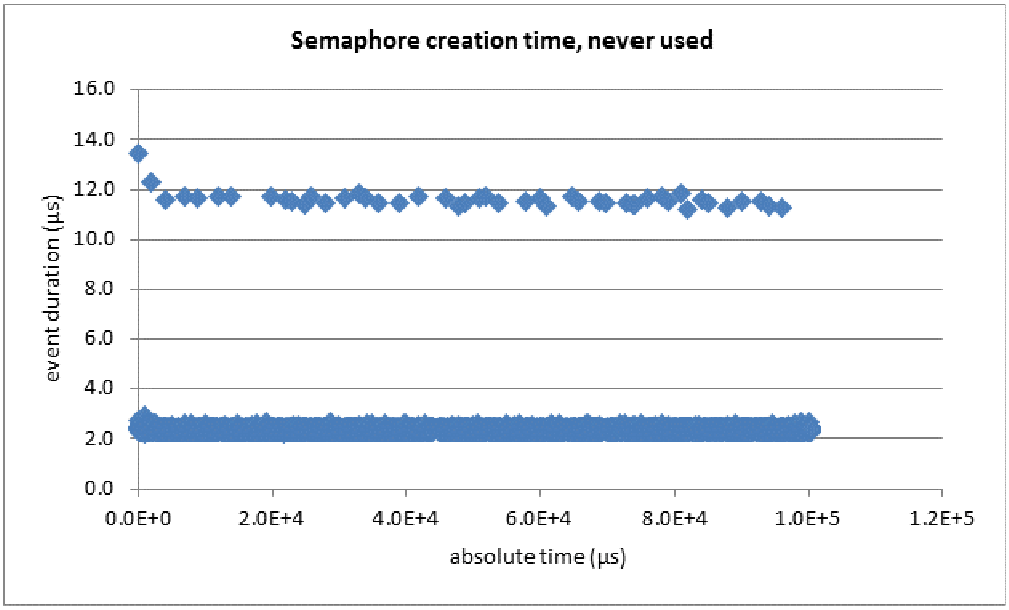
Test	result
Test succeeded	YES

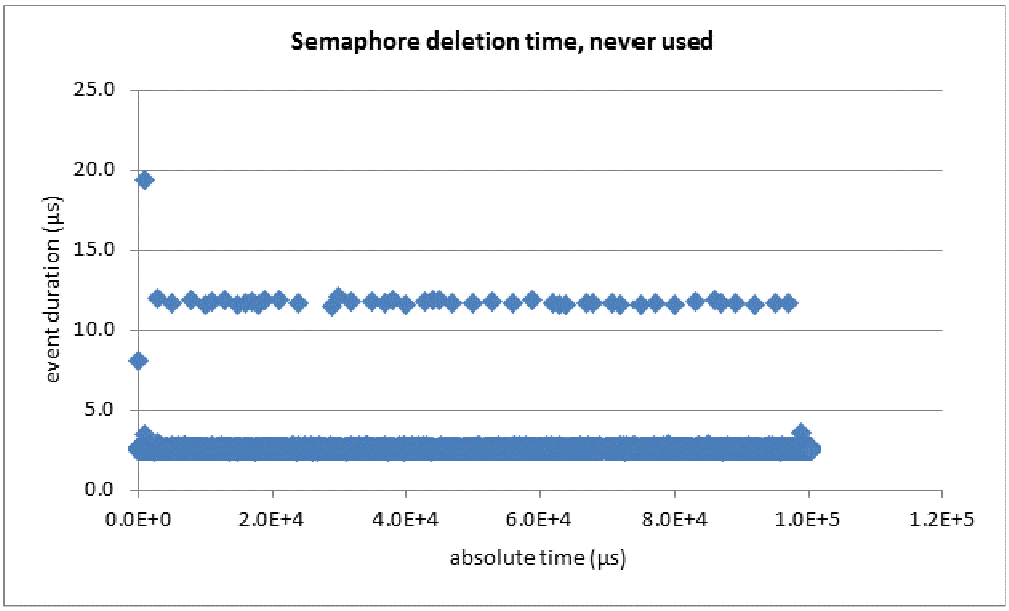
Test	Sample qty	Avg	Max	Min
Semaphore creation time, used	16383	2.5 µs	18.5 µs	2.3 µs
Semaphore deletion time, used	16383	2.6 µs	14.2 µs	2.4 µs
Semaphore creation time, never used	16383	2.4 µs	13.4 µs	2.2 µs
Semaphore deletion time, never used	16383	2.6 µs	19.4 µs	2.4 µs

4.4.3.2 Diagrams









4.4.4 Test acquire-release timings: non-contention case (SEM-P-ARN)

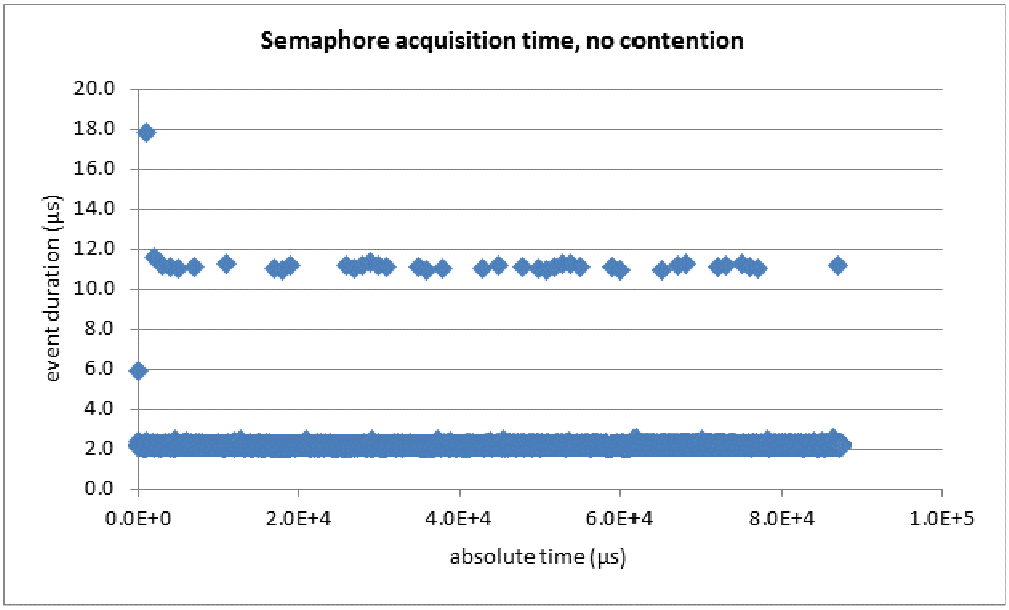
The "acquire-release timings: non-contention case" test measures the acquisition and release time in the non-contention case. Since in this test the semaphore does not neither block nor causes any rescheduling (thread switching), the duration of the call should be short.

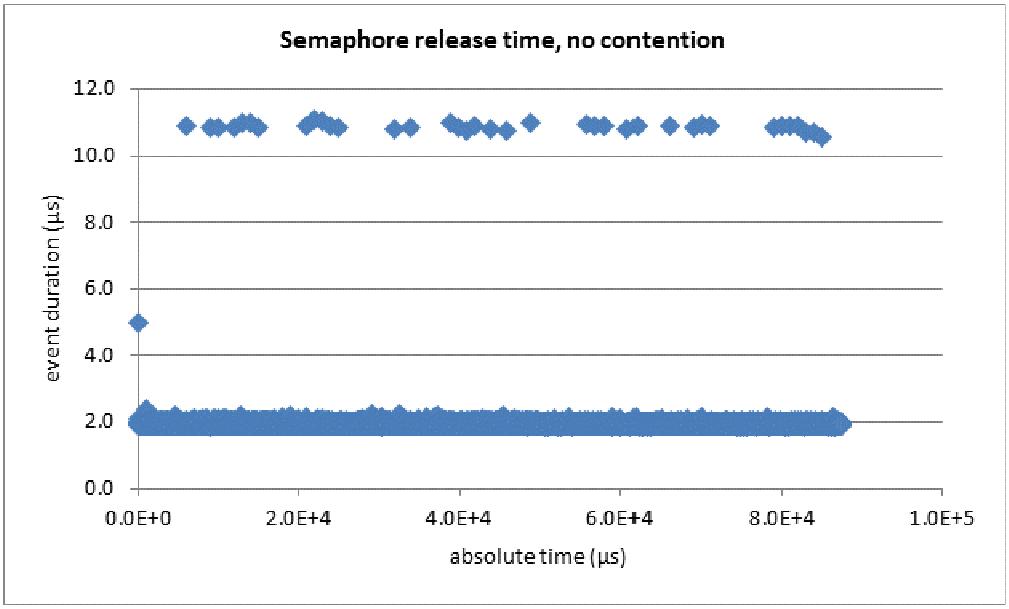
4.4.4.1 Test results

Test	result
Test succeeded	YES

Test	Sample qty	Avg	Max	Min
Semaphore acquisition time, no contention	16383	2.2 µs	17.9 µs	2.0 µs
Semaphore release time, no contention	16383	2.0 µs	11.1 µs	1.9 µs

4.4.4.2 Diagrams





4.4.5 Test acquire-release timings: contention case (SEM-P-ARC)

The "acquire release timings: contention case" test is performed to test the time needed to acquire and release a semaphore, depending on the number of threads blocked on the semaphore. It measures the time in the contention case when the acquisition and release system call causes a rescheduling to occur.

The purpose of this test is to see if the number of blocked threads has an impact on the times needed to acquire and release a semaphore. It attempts to answer the question: "How much time does the OS needs to find out which thread should be scheduled first?"

In this test, since each thread has a different priority, the question is how the OS handles these pending thread priorities on a semaphore. To have a more clear view on our test, you can take a look on the expanded diagrams during a small time frame (e.g. one test loop):

- We create 128 threads with different priorities. The creating thread has a lower priority than the threads being created.
- When the thread starts execution, it tries to acquire the ***semaphore***; but as it is taken, the thread stops and the kernel switch back to the creating thread. The time from the acquisition attempt (which fails) to the moment the creating thread is activated again is called here the "acquisition time". Thus, this time includes the thread switch time.
- Thread creation takes some time, so the time between each measurement point is large compared with most other tests.

- After the last thread is created and is blocked on the ***semaphore***, the creating thread starts to release the ***semaphore*** repeating this action the same number of times as the number of blocked threads on the semaphore.
- We start timing at the moment the ***semaphore*** is released which in turn will activate the pending thread with the highest priority, which will stop the timing (thus again the thread switch time is included).

Now, the most important part of this test is to see if the number of threads pending on a ***semaphore*** has an impact on release times. Clearly, it doesn't, so this is good.

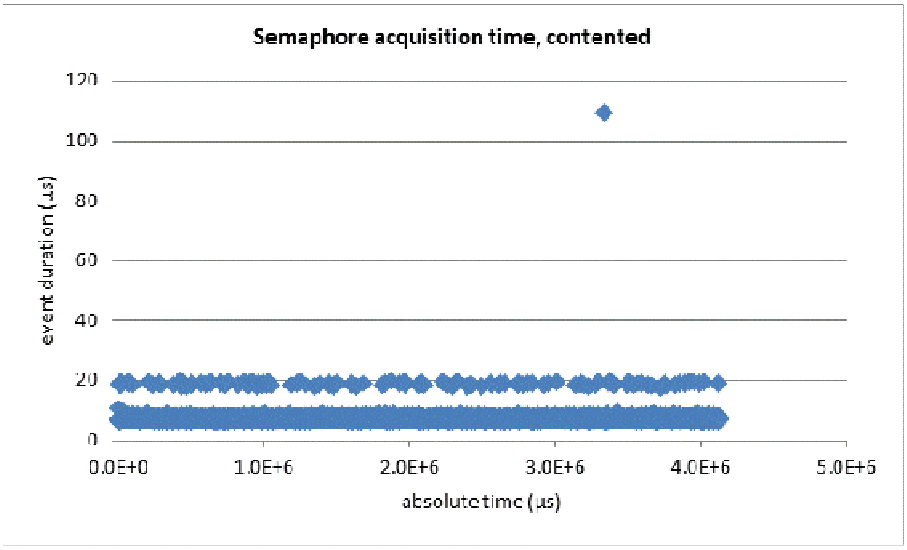
We detected one spike in the test.

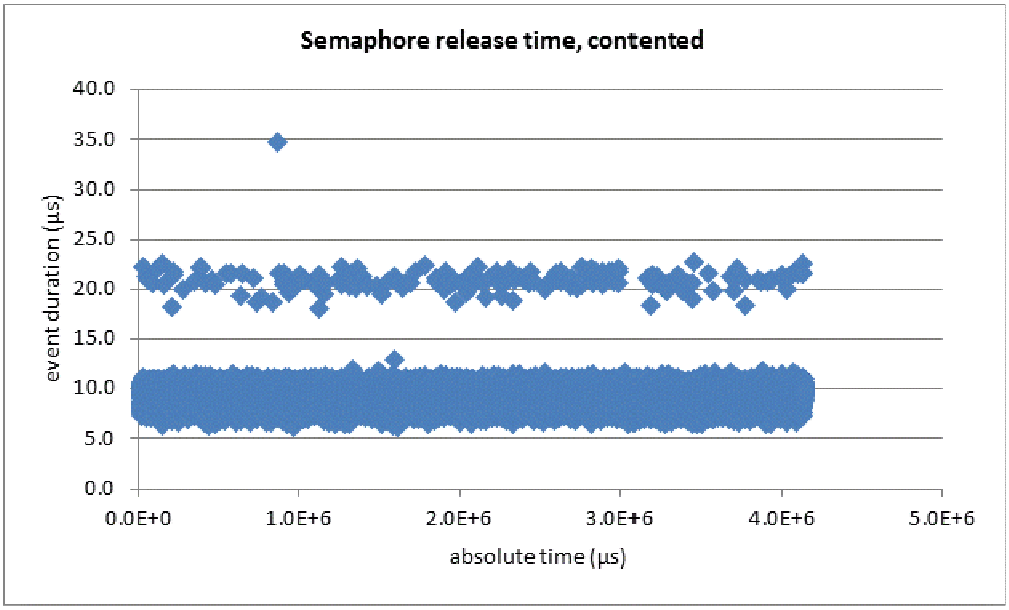
4.4.5.1 Test results

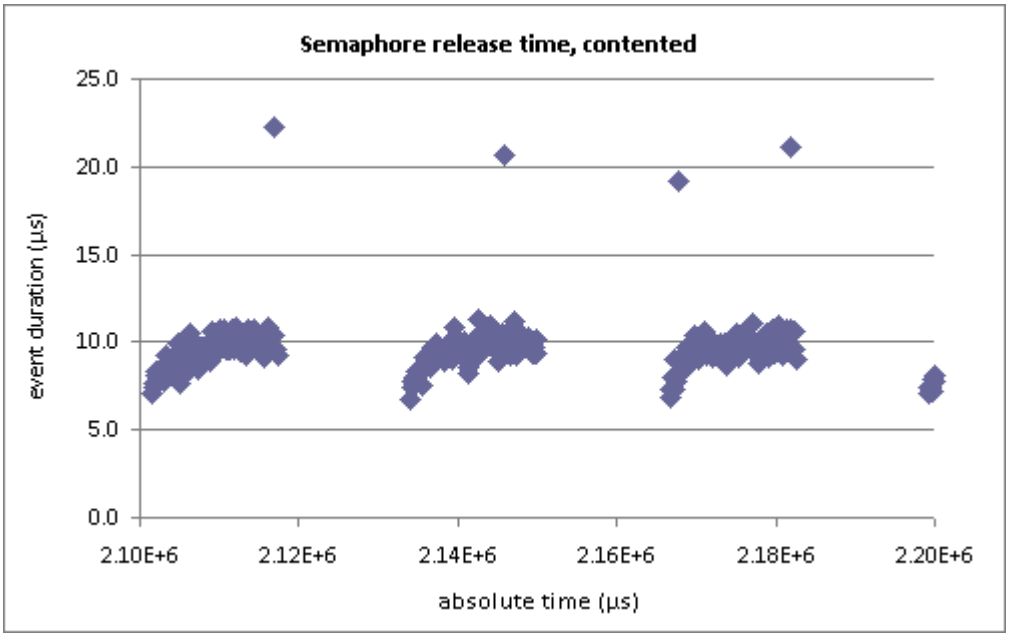
Test	result
Test succeeded	YES
Max number of threads pending	128

Test	Sample qty	Avg	Max	Min
Semaphore acquisition time, contented	16256	7.5 µs	110 µs	6.2 µs
Semaphore release time, contented	16256	9.6 µs	34.8 µs	6.2 µs

4.4.5.2 Diagrams







Zoomed in version of previous diagram.

4.5 Mutex tests (MUT)

Our "mutex tests" help us evaluate the behavior and performance of the mutual exclusive semaphore.

Although the mutual exclusive semaphore (further called mutex) is usually described as being the same as a counting semaphore where the count is one, this is not true. The behavior of a mutex is completely different than the behavior of a semaphore. Unlike semaphores, mutexes use the concept of a "lock owner", and can thus be used to prevent priority inversions. Semaphores cannot do this, and it goes without saying that mutexes (and not semaphores) should not be used semaphores for critical section protection mechanisms. In scope of the framework, this test will look into detail of a mutex system object that avoids priority inversion.

Remark that, Compact 7 has as well a ***Mutex*** system object; but this should be used only between processes as it always requires a long round-trip to the kernel even if the lock is not contented.

Remark as well that there exists InterlockedXXX functions, which use the available CPU instruction set to provide atomic behavior and as a result, these are fast.

4.5.1 Priority inversion avoidance mechanism (MUT-B-ARC)

The "priority inversion avoidance mechanism" test determines if the system call being tested prevents the priority inversion case. To check this possibility, the test artificially creates a priority inversion.

The behavior test was performed using the 2 scenarios: the Compact 7 mutex object, and the Critical section object.

The mutex object can be used between processes but therefore it requires of course each time a call to the kernel.

Therefore it is better to use the Critical Section object for protection between threads within a process. In this case, no kernel calls are needed if the lock is not contended, which increases a lot the speed of the lock under normal usage scenarios. Our performance tests will be done using the Critical Section object.

Priority inversion behaves as expected for both lock objects.

4.5.1.1 Test results

Test	result
Priority inversion avoidance system call present	Yes
System call used	InitializeCriticalSecton, EnterCriticalSection, LeaveCriticalSection. Behavior also tested for inter-process mutex: CreateMutex, WaitForSingleObject, ReleaseMutex
Test succeeded	YES
Priority inversion avoided	YES
Mechanism used if any?	Priority inversion cannot be disabled in **Compact 7**, which is a plus!

4.5.2 Mutex acquire-release timings: contention case (MUT-P-ARC)

The "mutex acquire-release timings: contention case" test is the same test as the "priority inversion avoidance mechanism" test described above, but performed in a loop. In this case, we measure the time needed to acquire and release the mutex in the priority inversion case.

Our test is designed so that the acquisition enforces a thread switch:

- The acquiring thread is blocked
- The thread with the lock is released.

We measured the acquisition time from the request for the mutex acquisition to the activation of the lower priority thread with the lock.

Note that before the release, an intermediate priority level thread is activated (between the low priority one having the lock and the high priority one asking the lock). Due to the priority inheritance, this thread does not start to run (the low priority thread having the lock inherited the high priority of the thread asking the lock).

We measured the release time from the release call to the moment the thread requesting the mutex was activated; so this measurement also includes a thread switch.

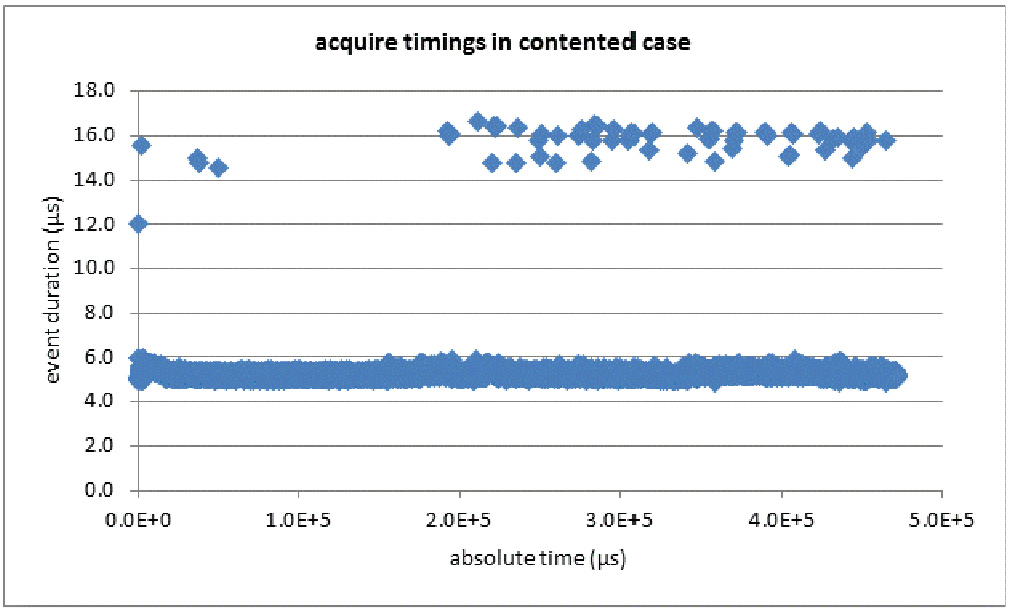
The clock tick interrupt can be clearly seen (as usual) (figures of section 4.5.2.2).

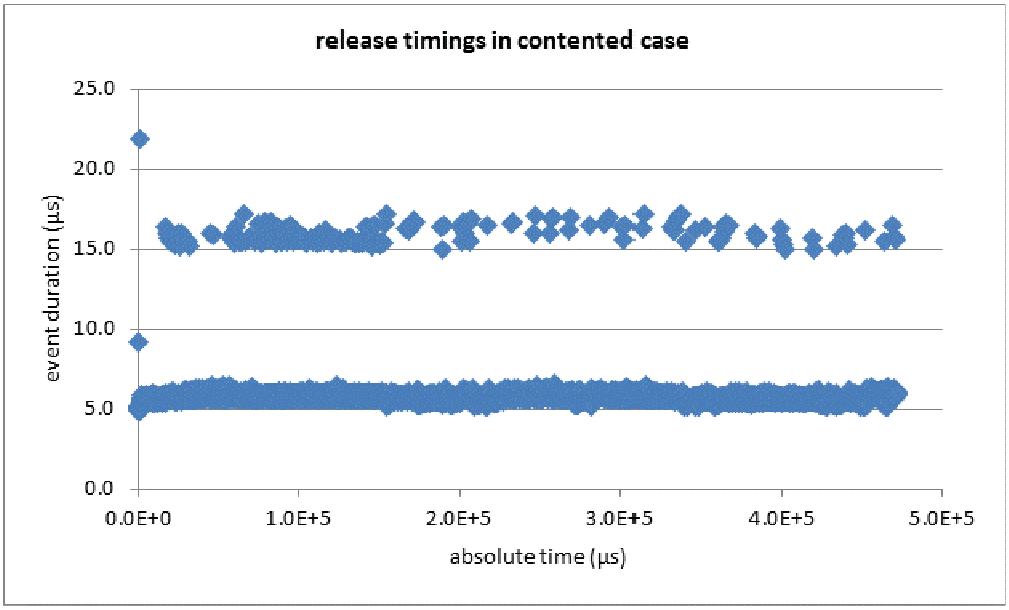
4.5.2.1 Test results

Test	result
Test succeeded	Yes

Test	Sample qty	Avg	Max	Min
Mutex acquisition time, contention	16383	5.3 µs	16.6 µs	4.9 µs
Mutex release time, contention	16383	5.8 µs	21.9 µs	4.9 µs

4.5.2.2 Diagrams:





4.5.3 Mutex acquire-release timings: non-contention case (MUT-P-ARN)

The "mutex acquire-release timings: no contention case" test measures the overhead incurred by using a lock when this lock is not owned by any other thread. Well-designed software will use non-contended locks most of the time, and only in some rare cases the lock will be taken by another thread.

Therefore, it is important that the non-contention case should be fast. Remark that this is only possible if:

- The CPU supports some type of atomic instruction, so that no system call is needed when no contention is detected.
- A lock is not shared between processes.

The last requirement is valid only when the Critical Section object in Compact 7 is used, because the Mutex object is an object meant to be used in a shared process scenario and does not contain this optimization.

Performance is excellent and too small to measure!

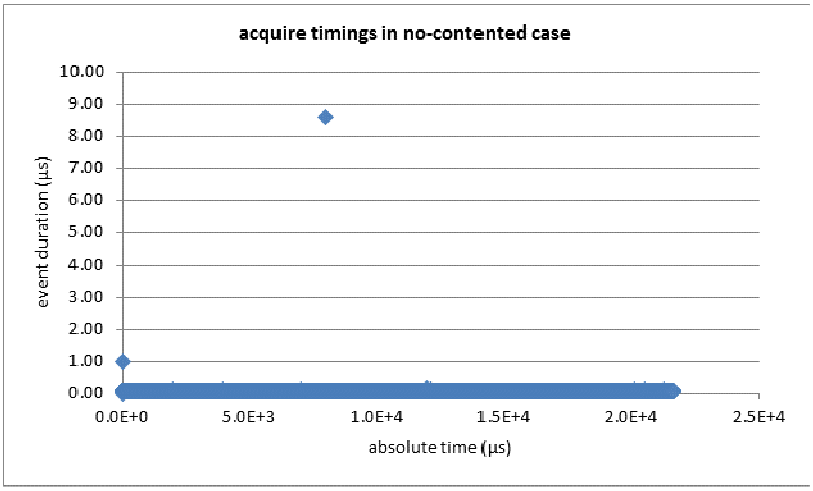
Only a couple of clock ticks disturb the measurement.

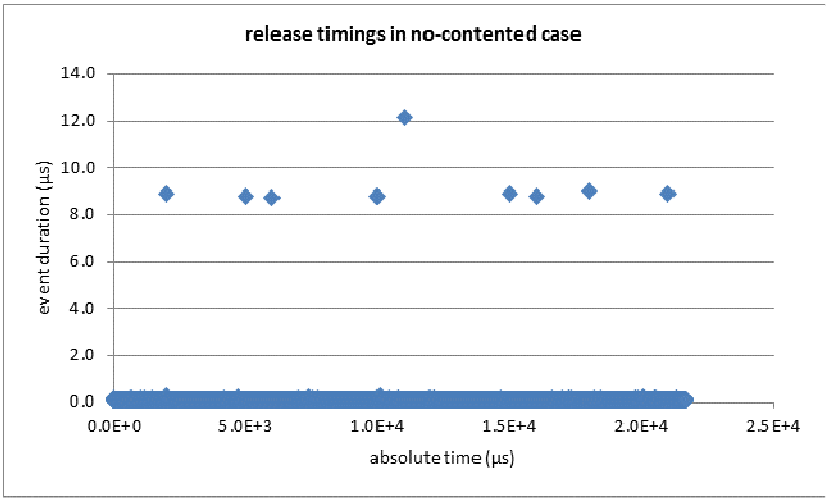
4.5.3.1 Test results

Test	result
Test succeeded	Yes

Test	Sample qty	Avg	Max	Min
Mutex acquisition time, no contention	16383	<0.1 µs	8.6 µs	<0.1 µs
Mutex release time, no contention	16383	<0.1 µs	12.2 µs	<0.1 µs

4.5.3.2 Diagrams:





4.6 Interrupt tests (IRQ)

"Interrupt tests" evaluate how the operating system performs when handling interrupts.

Interrupt handling is a key system capability of real-time operating systems. Indeed, RTOSs are typically event driven.

For our interrupt tests, we use a general purpose timer on the BeagleBoard-XM chip to generate interrupts, in the same way that we use a general purpose timer on the chip for tracing. The timer we used has an independent programmable wrap-around timer, which protects it from influence by the RTOS clock. This protection allows us to guarantee that an independent interrupt source is not synchronized in any way with the platform being tested.

4.6.1 Interrupt latency (IRQ_P_LAT)

The "interrupt latency" test measures the time it takes to switch from a running thread to an interrupt handler. This time is measured from the moment the running thread is interrupted, so the measurement does not take into account the hardware interrupt latency.

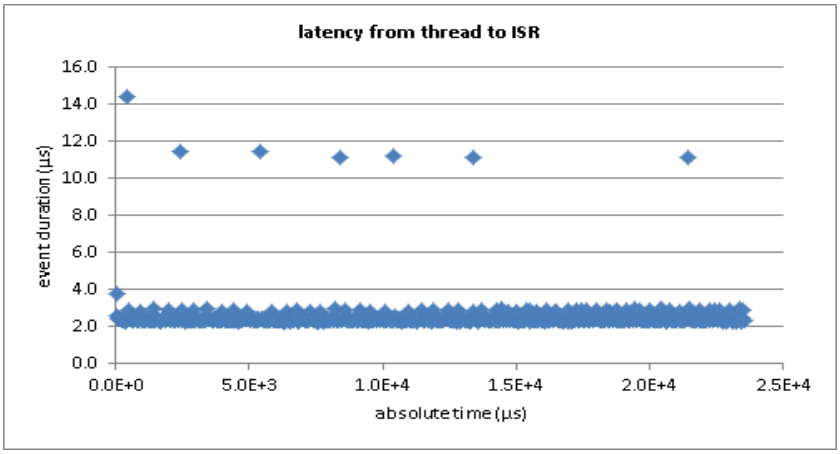
Remark that in Compact 7, the interrupt handler is already a thread, so it includes a thread switch. This is also the reason why we do not do the interrupt to thread latency test. So you should compare this with the TLT (Thread Latency Test) on other RTOS!

The clock time is easily detected again (it has the highest interrupt level).

4.6.1.1 Test results

Test	Sample qty	Avg	Max	Min
Interrupt dispatch latency	598	2.5 us	14.4 us	2.2 us

4.6.1.2 Diagrams



4.6.2 Interrupt to interrupted thread latency (IRQ_P_DLT)

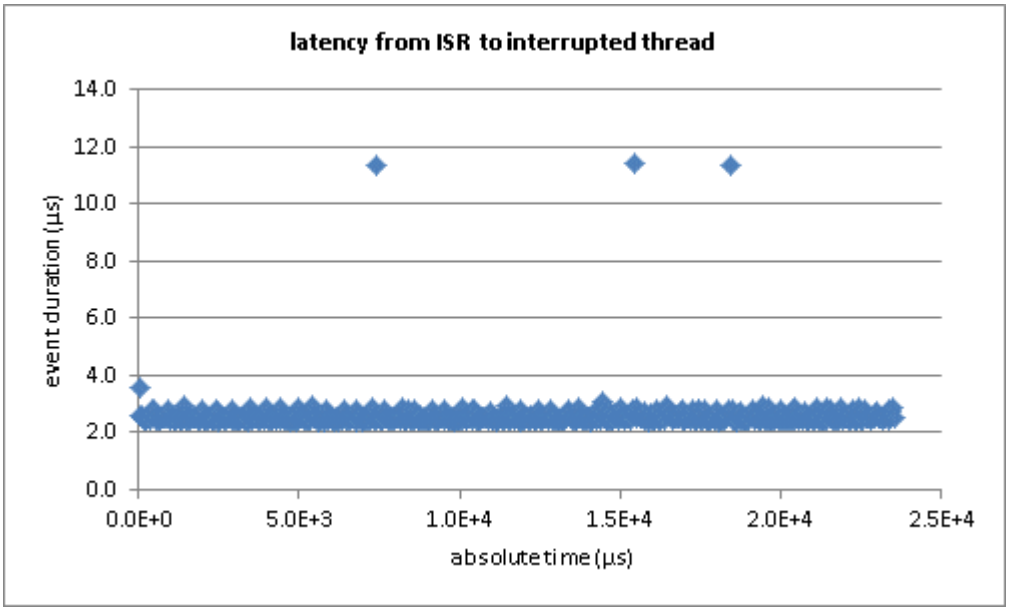
4.6.2.1 Test results

The "interrupt dispatch latency" test measures the time the OS takes to switch from the interrupt handler back to the interrupted thread.

4.6.2.2 Test results

Test	Sample qty	Avg	Max	Min
Latency from ISR to waken-up thread	598	2.6 us	11.5 us	2.4 us

4.6.2.3 Diagrams



4.6.3 Maximum sustained interrupt frequency (IRQ_S_SUS)

The "maximum sustained interrupts frequency" test measures the probability that an interrupt might be missed. It attempts to answer the question: Is the interrupt handling duration stable and predictable?

Remark first that for this test, an interrupt service thread is used; so compared with other RTOS, extra context switch latency should be added (needed to be added twice in this case: interrupt start and interrupt leave).

We note that the rather long duration to handle the clock tick interrupt is due to the implementation by the BSP vendor, which in this case came from a 3rd party. We expect that improvements to the BSP would decrease the long duration.

This test is done in 3 phases:

- 1000 interrupts as an initial phase: a fast test just to see where we have to start searching.
- 1 000 000 interrupts as a second phase based on the results from the first phase. This test still takes less than a minute and gives already accurate results.
- 1 billion interrupts as a last phase, which takes few hours, and sometimes more than 24 hours, depending on the used platform and OS. This phase is done to verify stability; therefore, we cannot run this phase many times, especially when it comes to large interrupt latencies. Normally we do this on a billion interrupts, but as the time between interrupts had to be so long we limited it to 100 million interrupts.

As one can observe in the above interrupt test results, the interrupt latency is 2.5 µs in the best case. But due to the clock interrupt, the latency increases. For a long run, we need about 26µs not to miss one interrupt. This is almost twice longer than the values obtained on the Pentium II 233MHz platform. This was however also the case for the other RTOS tested on this platform.

4.6.3.1 Test results

Interrupt period	#interrupts generated	#interrupts serviced	#interrupts lost
10 µs	10 000	9 998	2
11 µs	10 000	9 999	1
12 µs	10 000	10 000	0
13 µs	1 000 000	999 999	1
14 µs	1 000 000	1000 000	0
15 µs	10 000 000	9 999 995	5
17 µs	10 000 000	9 999 998	2
18 µs	10 000 000	9 999 998	2
19 µs	10 000 000	10 000 000	0
19 µs	100 000 000	99 999 985	15
22 µs	100 000 000	99 999 994	6
24 µs	100 000 000	99 999 997	3
26 µs	100 000 000	100 000 000	0

4.7 Memory tests

This examines the memory leaks of OS.

4.7.1 Memory leak test (MEM_B_LEK)

This test continuously create/remove objects in the operating system (threads, ***semaphores***, ***mutexes*** …).

Test	result
Test succeeded	YES
Test duration (how long we let the endless loop run)	>10h
Number of main test loops done	> 50 000

5 Appendix A: Vendor comments

All vendor comments were integrated within the document as there were no disagreements.

6 Appendix B: Acronyms

Acronym	Explanation
API	Application Programmers Interface: calls used to call code from a library or system.
BSP	Board Support Package: all code and device drivers to get the OS running on a certain board
DSP	Digital Signal Processor
FIFO	First In First Out: a queuing rule
GPOS	General Purpose Operating System
GUI	Graphical User Interface
IDE	Integrated Development Environment (GUI tool used to develop and debug applications)
IRQ	Interrupt Request
ISR	Interrupt Servicing Routine
MMU	Memory Management Unit
OS	Operating System
PCI	Peripheral Component Interconnect: bus to connect devices, used in all PCs!
PIC	Programmable Interrupt Controller
PMC	PCI Mezzanine Card
PrPMC	Processor PMC: a PMC with the processor
RTOS	Real-Time Operating System
SDK	Software Development Kit
SoC	System on a Chip